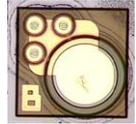




# VCC-85B8H

## 850nm 8mW VCSEL Chip



### Features

- 850nm multi-emitter VCSEL chip
- Output power: 8mW
- Gaussian beam profile
- Multiple mesa type
- High reliability

### Applications

- Consumer electronics
- Safety sensor
- Illumination light source
- Proximity sensor

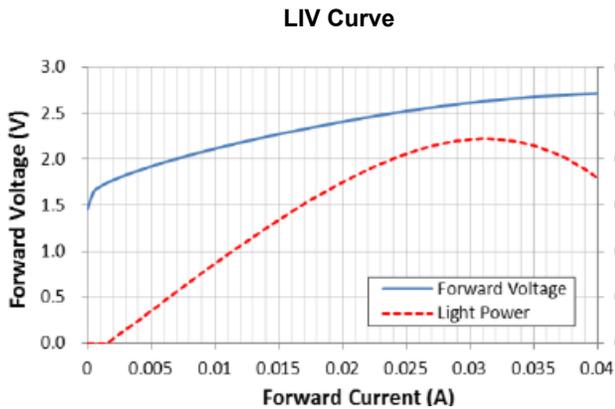
### Specifications

Absolute Maximum Ratings				
Parameters	Min.	Max.	Unit	Conditions
Storage Temperature	-40	85	°C	
Operating Temperature	-10	60	°C	
Continuous Forward Current		15	mA	

Electro-Optical Characteristics (T <sub>a</sub> =25°C unless otherwise stated)						
Parameters	Symbol	Min.	Typ.	Max.	Unit	Conditions
Threshold Current	I <sub>th</sub>		2.0		mA	CW
Slope Efficiency	η		1.0		W/A	I <sub>f</sub> =10mA
Optical Output Power	P <sub>o</sub>		8		mW	I <sub>f</sub> =10mA
Peak Wavelength	λ <sub>p</sub>	840	850	860	nm	I <sub>f</sub> =10mA
Beam Divergence	Θ		13		°	P <sub>o</sub> = 8mW (FWHM)
Operating Voltage	V <sub>f</sub>		2.1	2.4	V	I <sub>f</sub> =10mA
Breakdown Voltage	V <sub>b</sub>	-10			V	
Series Resistance	R <sub>d</sub>		35		Ohm	I <sub>f</sub> =10mA

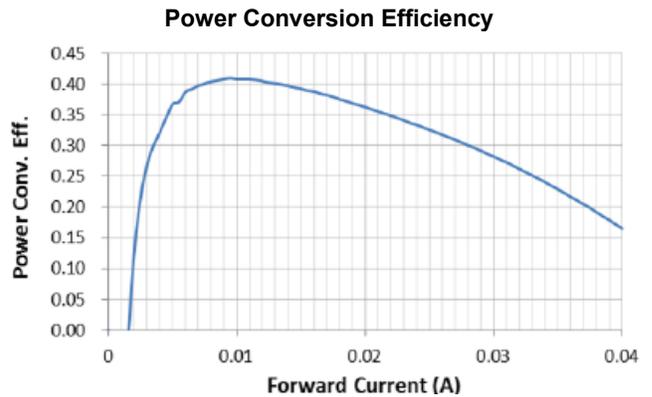
Thermal Characteristics						
Parameters	Symbol	Min.	Typ.	Max.	Unit	Conditions
I <sub>th</sub> Temperature Variation	ΔI <sub>th</sub>		1.0		mA	T <sub>a</sub> =-10 to 70°C
λ Temperature Coefficient	Δλ/ΔT		0.06		nm/°C	T <sub>a</sub> =-10 to 70°C, I <sub>f</sub> =10mA

**Typical Characteristics**



Test PKG sample: TO-Can type, TO-46

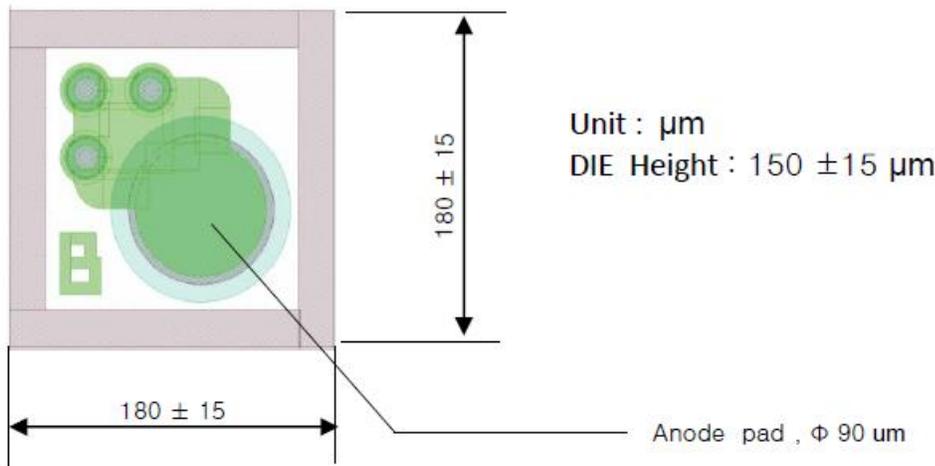
Test condition: CW Mode:  $I_f$  step interval 2mA, Delay time 2msec



Test PKG sample: TO-Can type, TO-46

Test condition: CW Mode:  $I_f$  step interval 2mA, Delay time 2msec

**Outline Dimensions**



**Additional Notes**

- The inherent design of this component causes it to be sensitive to electrostatic discharge (ESD). To prevent ESD-induced damage and/or degradation to equipment, take normal ESD precautions when handling this product.
- Specifications are subject to change without notice.